



N-Channel Enhancement MOSFET

Features

- Drain-Source Breakdown Voltage V_{DS} 60 V
- Drain-Source On-Resistance
 - $R_{DS(ON)}$ 3.0 Ω , at V_{GS} = 10V, I_{DS} = 500mA
 - $R_{DS(ON)}$ 4.0 Ω , at V_{GS} = 4.5V, I_{DS} = 200mA
- Continuous Drain Current at $T_A=25^\circ\text{C}$,
 - I_D = 300mA
- Advanced high cell density Trench Technology
- RoHS Compliance & Halogen Free
- ESD protection 1.5KV

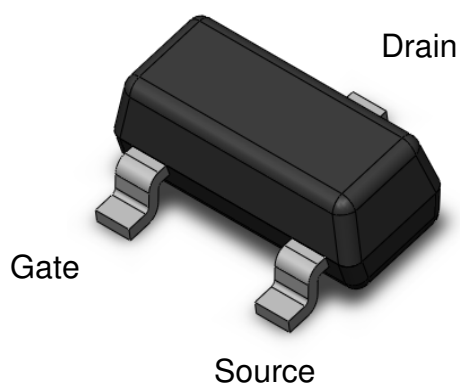
Applications

- Cellular phone
- Notebook
- Power management

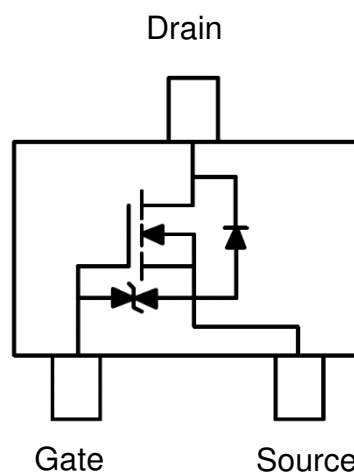
Description

The CTL0036NS-R3 is the N-Channel logic enhancement mode power field effect transistors are produced using high cell density, DMOS trench technology. This high density process is especially tailored to minimize on-state resistance.

Package Outline



Schematic



**Absolute Maximum Rating at 25°C**

Symbol	Parameters	Ratings	Units	Notes
V_{DS}	Drain-Source Voltage	60	V	
V_{GS}	Gate-Source Voltage	±20	V	
I_D	Continuous Drain Current @ $T_A=25^\circ\text{C}$	300	mA	1
I_{DM}	Pulsed Drain Current	2000	mA	1
P_D	Total Power Dissipation @ $T_A=25^\circ\text{C}$	0.35	W	2
T_{STG}	Storage Temperature Range	-55 to 150	°C	
T_J	Operating Junction Temperature Range	-55 to 150	°C	

Thermal Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$R_{\theta JA}$	Thermal Resistance Junction-Ambient (t=10s)		-	357	-	°C /W	1,4

**Electrical Characteristics** $T_A = 25^\circ\text{C}$ (unless otherwise specified)**Static Characteristics**

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$B_{V_{DS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	60	-	-	V	
I_{DSS}	Drain-Source Leakage Current	$V_{DS}=60V, V_{GS}=0V$	-	-	1	μA	
I_{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	± 10	μA	

On Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$R_{DS(ON)}$	Drain-Source On-Resistance	$V_{GS}=10V, I_D=500mA$	-	-	3	Ω	3
		$V_{GS}=4.5V, I_D=200mA$	-	-	4	Ω	
$V_{GS(TH)}$	Gate-Source Threshold Voltage	$V_{GS}=V_{DS}, I_D=250\mu A$	1.0	-	2.5	V	3

Dynamic Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
C_{ISS}	Input Capacitance	$V_{DS}=25V,$ $V_{GS}=0V,$ $f=1MHz$	-	-	35	pF	
C_{OSS}	Output Capacitance		-	-	10		
C_{RSS}	Reverse Transfer Capacitance		-	-	5		

Switching Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$T_{D(ON)}$	Turn-On Delay Time	$V_{DS}=30V, V_{GS}=10V,$ $R_G=150\Omega, I_D=200mA$ $R_G=10\Omega$	-	-	20	ns	
$T_{D(OFF)}$	Turn-Off Delay Time		-	-	40		
Q_G	Total Gate Charge	$V_{DS}=15V, V_{GS}=4.5V,$ $I_D=200mA$	-	-	0.8	nC	

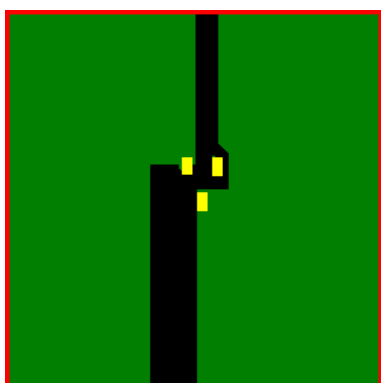


Drain-Source Diode Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
V _{SD}	Body Diode Forward Voltage	V _{GS} = 0V, I _D = 200mA		0.82	1.3	V	
I _{SD}	Body Diode Continuous Current				500	mA	1

Note:

- 1. The power dissipation is limited by 150°C junction temperature.
- 2. Device mounted on a glass-epoxy board



FR-4
25.4 × 25.4 mm .
2 Oz Copper

Actual Size

- 3. The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
- 4. Thermal Resistance follow JESD51-3.



Typical Characteristic Curves

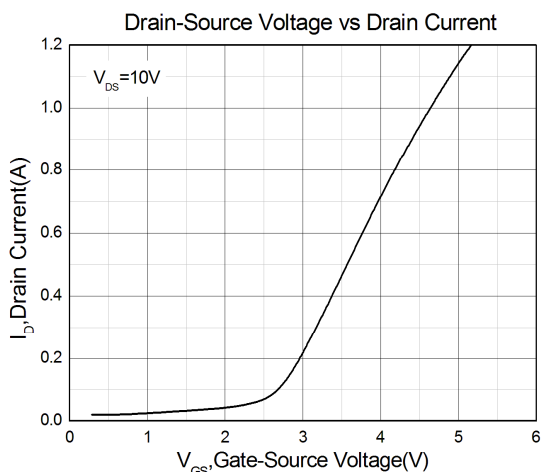


Figure 1

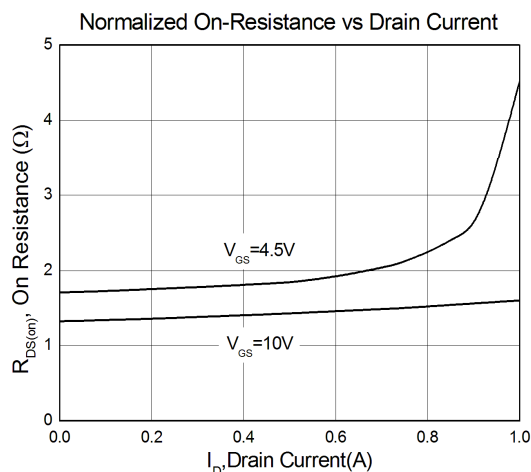


Figure 2

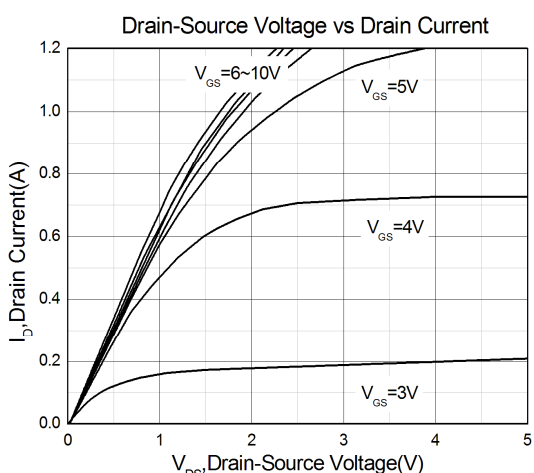


Figure 3

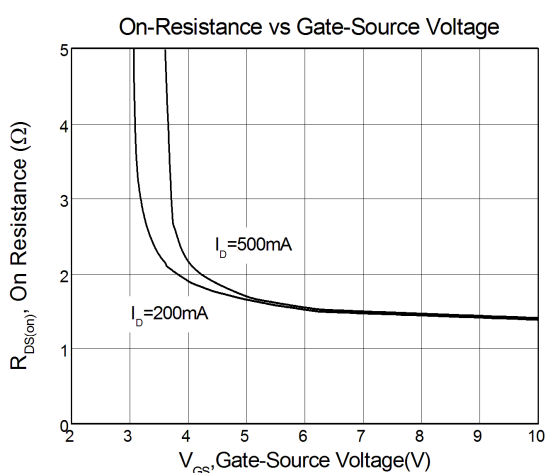


Figure 4

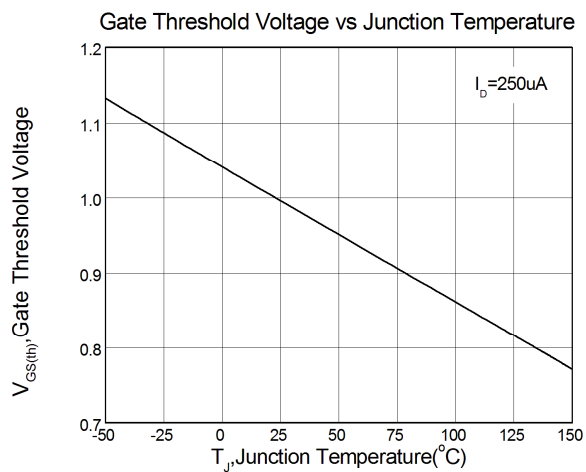


Figure 5

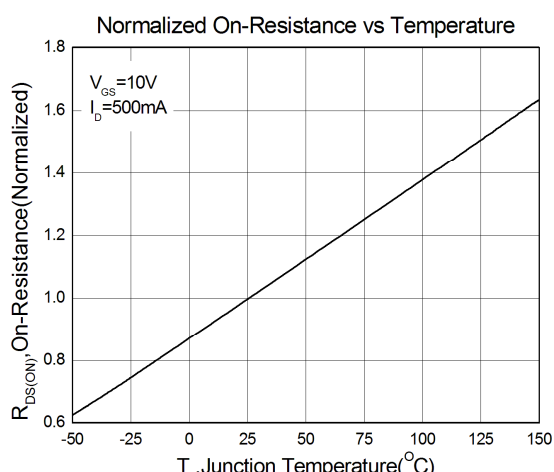


Figure 6



Test Circuits & Waveforms

Figure 7: Gate Charge Test Circuit

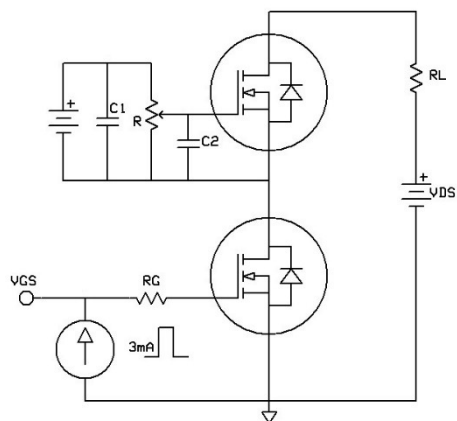


Figure 8: Gate Charge Waveform

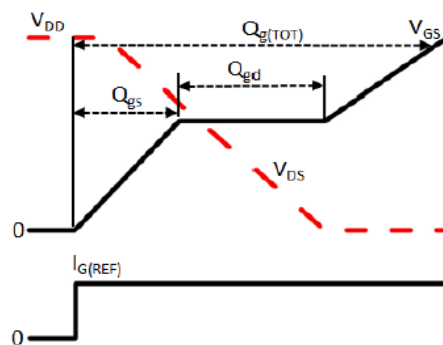


Figure 9: Switching Time Test Circuit

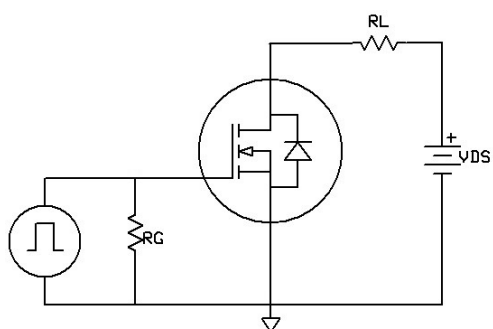
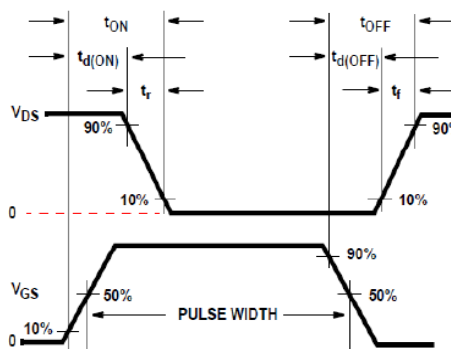
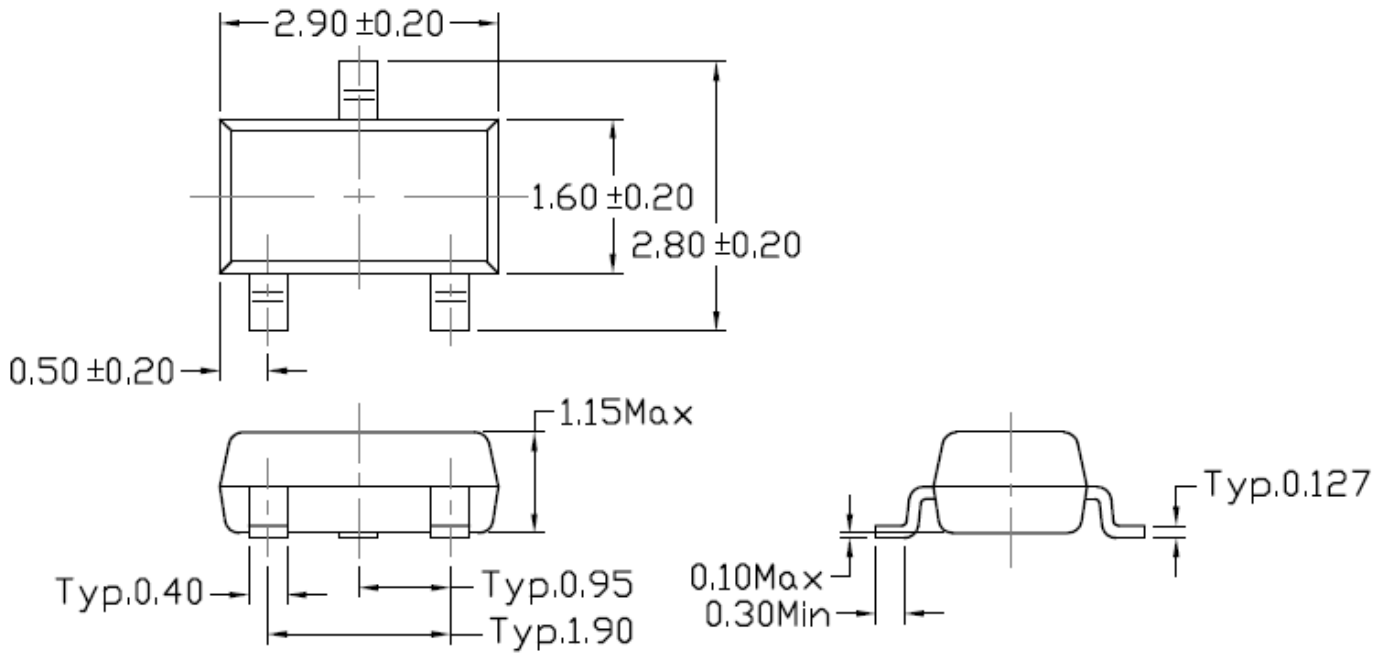


Figure 10: Switching Time Waveform

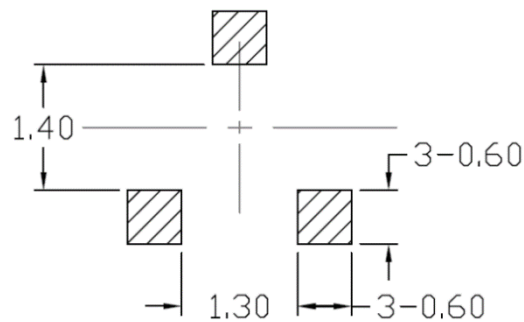




Package Dimension(SC-59)



Recommended pad layout for surface mount leadform

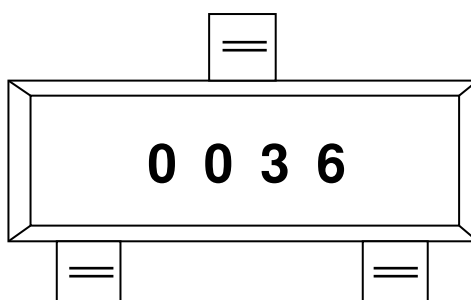




CTL0036NS-R3

N-Channel Enhancement MOSFET

Marking Information



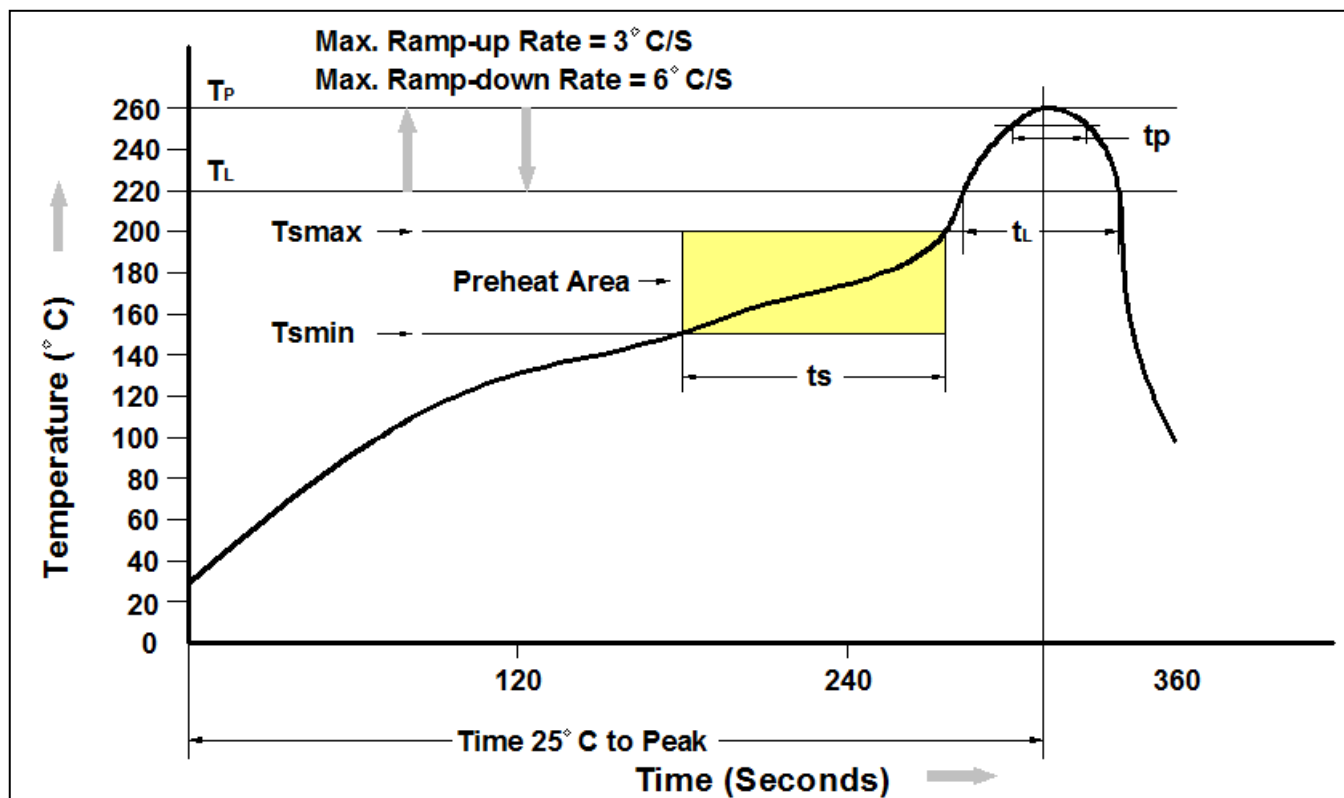
0036 : Device Number

Ordering Information

<i>Part Number</i>	<i>Description</i>	<i>Quantity</i>
CTL0036NS-R3	SC-59 Reel	3000 pcs



Reflow Profile



Profile Feature	Pb-Free Assembly Profile
Temperature Min. (T _{min})	150 °C
Temperature Max. (T _{max})	200 °C
Time (t _s) from (T _{min} to T _{max})	60-120 seconds
Ramp-up Rate (t _L to t _P)	3°C/second max.
Liquidous Temperature (T _L)	217 °C
Time (t _L) Maintained Above (T _L)	60 – 150 seconds
Peak Body Package Temperature	260 °C +0 °C / -5 °C
Time (t _P) within 5 °C of 260 °C	30 seconds
Ramp-down Rate (T _P to T _L)	6°C/second max
Time 25 °C to Peak Temperature	8 minutes max.



DISCLAIMER

CT MICRO RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. CT MICRO DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

CT MICROELECTRONICS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT EXPRESS WRITTEN APPROVAL OF CT MICROELECTRONICS LTD.

- 1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instruction for use provided in the labelling, can be reasonably expected to result in significant injury to the user.*
- 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.*